

Silicon Carbide: A Brief Overview

March 14, 2019 ROHM Semiconductor, USA Applications Engineering

© 2019 ROHM Co.,Ltd.



- Where we are
 - SiC Schottky Barrier Diodes
 - SiC MOSFETs (Discrete)
 - SiC Power Modules
- Where we are Headed
 - Packages with Kelvin connection
 - 4th Generation SiC MOSFETs
- Tips for Successful Use
 - Gate Driver Criteria
 - Consider the Isolated DC/DC Converter
 - Check the Gate Drive signal
 - Check the overshoot voltage on the Drain
 - Look for current shoot-through

SiC: A Brief Overview

• SiC Diodes

- The #1 choice as the "catch" diode for PFC Boost applications
- Your choice of 80 diodes from 2A 40A, from 650V 1200V (20 are AECQ qualified)
- Choice of 2nd Gen or 3rd Gen devices (as of now only 2nd Gen are AECQ qualified)
- 3rd Gen offers the following improvements:
 - Improved Surge current rating (I_{FSM})
 - Lower Forward Voltage Drop (V_F)
 - Lower leakage current (I_R)



R(0)-11

Reverse recovery characteristics





*These data are provided to show a result of evaluation done by ROHM for your reference. ROHM does not guarantee any of the characteristics shown here.



Package	TO-220	TO-220FM	TO-247	D2pack	Bare dies
Rated voltage	ROMM K A	KA	AKA	(LPTL) K Romm N/C A	
650V	6A~20A	6A~20A	20A~40A	2A~20A	6A~20A(MP) 30A~100A(DS)
1200V	5A~20A		10A~40A		5A~20A 30A, 50A
1700V					10A~50A

Automotive grade AEC-Q101 qualified

650V	6A~20A	20A~40A	6A~20A
1200V	5A~20A	10A~40A	

3rd Gen SiC-SBD portfolio



Line up

650V	P/N	2A	4A	6A	8A	10A	12A	15A	20A	
TO-220ACP-2L	SCS3xxAH (halogen free)	\checkmark								
TO-220FM-2L	SCS3xxAM		\checkmark							
TO-263AB-3L (D2PAK/LPTL)	SCS3xxAJ New	\checkmark	ROHM							

Note: Automotive (AECQ) Grade is in process.

Mass Production

SiC Discrete MOSFETs

- 2nd Generation devices utilizing **Planar** technology
 - Largest die size for a given ON resistance (R_{DS(on)})
 - Longest Short-Circuit Withstand time (SCWT is about 10 microseconds)
- 3rd Generation devices utilizing **Trench** technology
 - About half the ON resistance $(R_{DS(on)})$ for a given die size
 - Short-Circuit Withstand time is lower (SCWT is about 5 microseconds)
 - Reduced Input capacitance (C_{iss}) makes it easier to drive
 - Less switching energy losses for both Turn-On and Turn-Off





2nd Generation DMOS Portfolio





P/N

SCT2xxxKE

SCH2080KE SBD co-pack



G

DS

1700V	P/N	750mΩ	1150mΩ
TO-3PFM	SCT2H12NZ		$\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{\mathbf{$
TO-268-2L	SCT2xxxNY	\checkmark	\checkmark



450mΩ

ROHM

GDS

280mΩ

160mΩ



80mΩ



1200V

TO-247



HM

650V	Part No. / Status	17mΩ	22mΩ	30mΩ	60mΩ	80mΩ	120mΩ)●(ROHM
TO-247N	SCT3xxxAL on MP	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	
TO-247-4L	SCT3xxxAR MP: Q2/19			\checkmark	\checkmark	\checkmark		
TO-263-7L	SCT3xxxAW MP: Q2/19			\checkmark	\checkmark	\checkmark	\checkmark	ROHM

1200V	Part No. / Status	22mΩ	30mΩ	40mΩ	80mΩ	105mΩ	160mΩ)●(ROHM
TO-247N	SCT3xxxKL on MP	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	
TO-247-4L	SCT3xxxKR MP: Q2/19			\checkmark	\checkmark	\checkmark		ROHI
TO-263-7L	SCT3xxxKW MP: Q2/19			\checkmark	\checkmark	\checkmark	\checkmark	ROHM

* as of Oct 2018

MP: Mass production

✓ Mass Production ✓ Under development



Automotive grade (AEC-Q101 qualified)



650V	Part No. / Status	17mΩ	22mΩ	30mΩ	60mΩ	80mΩ	120mΩ) ● (ROHM
TO-247N	SCT3xxxALHR New	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	
TO-263-7L	SCT3xxxAWHR MP: Q2/19			\checkmark	\checkmark	\checkmark	\checkmark	

1200V	Part No. / Status	22mΩ	30mΩ	40mΩ	80mΩ	105mΩ	160mΩ)●(ROHM
TO-247N	SCT3xxxKLHR New	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	\checkmark	
TO-263-7L	SCT3xxxKWHR MP: Q2/19			\checkmark	\checkmark	\checkmark	\checkmark	ROHI

* as of Dec 2018

Mass Production V Under development

MP: Mass production





✓ 1200V
✓ 80, 120, 180A

E type

✓ 1200, 1700V
✓ 180, 250, 300A
✓ Higher voltage



- ✓ 1200V
- ✓ 400, 600A
- ✓ High current
- ✓ Low inductance





Package evolution of full SiC power modules



>	Low stray	inductance
	L _S =10nH	

- > High current rating ~600A
- Compatible outline with market available IGBT modules

	Voltage Rating (V)	Current Rating (A)	Case Type	MOS device generation	Circuit	Ls (nH)	Thermistor
BSM400D12P2G003	1200	400	G	2G(planer)	Half bridge	10	\bigcirc
BSM400D12P3G002	1200	400	G	3G(Trench)	Half bridge	10	\bigcirc
BSM600D12P3G001	1200	600	G	3G(Trench)	Half bridge	10	0
BSM400C12P3G202	1200	400	G	3G(Trench)	Chopper	10	\bigcirc
BSM600C12P3G201	1200	600	G	3G(Trench)	Chopper	10	\bigcirc



Patented

1件

0

0

100

Vsurge

200

Feature

> Lower stray inductance by original main terminal structure



Current

300



Module type	Vdss	lo(Tc=60°C)	Part No.		MOS	Topology	Status			
C type		80A	BSM080D12P2C008			Half bridge	on MP			
		120A	BSM120D12P2C005	2G	Planar	Half bridge	on MP			
The second secon	1200V		BSM120C12P2C201			Chopper (boost)	on MP			
122 v 15 6 mm		100 4	BSM180D12P3C007	20	Tranch	Half bridge	on MP			
122 × 40.0 mm		TOUA	BSM180C12P3C202	30	Trench	Chopper (boost)	on MP			
E type		100 4	BSM180D12P2E002			Half bridge	on MP			
				TOUA	BSM180C12P2E202	2G	Planar	Chopper (boost)	on MP	
	1200\/		BSM300D12P2E001			Half bridge	on MP			
a s	12000	2004	BSM300D12P3E005 *	3G		Half bridge	2019			
		300A	BSM300C12P3E201		Trench	Chopper (boost)	on MP			
152 x 62 mm			BSM300C12P3E301 *			Chopper (buck)	2019			
	1700V	250A	BSM250D17P2E004	2G	Planar	Half bridge	on MP	NE		
G type			BSM400D12P2G003	2G	Planar	Half bridge	on MP			
13		400A	BSM400D12P3G002			Half bridge	on MP			
200	1200V	V	BSM400C12P3G202	20	Trench	Chopper (boost)	on MP			
152 x 62 mm			BSM600D12P3G001	30		Half bridge	on MP			
Low Ls 10nH		OUUA	BSM600C12P3G201			Chopper (boost)	on MP			

* Under Development

Where we are headed - Package roadmap





© 2018 ROHM Co.,Ltd.

PKG images are for illustrative purpose only.

As of Feb. 2018 P. 14



<u>1200V target spec (compared with Gen 3)</u>

- 1) Ron*A: reduced by 50%
- 2) SCWT : > 5 μ sec
- 3) Vgs rating : -10 to 20V (Vgs op is 15V)
- 4) Int $R_g : <50\%$
- 5) C_{gd} : reduced
- 6) C_{gd}/C_{gs} : reduced

Target design sample : 2019 Q3 (Chip sample)

	Gen 2 2012~	Gen 3 2016~	Gen4 2019~				
Structure	Planar	Trench	Trench				
Vdsmax	1200V						
RonA	8.2mΩcm2	4.1mΩcm2	2.3mΩcm2				
SCWT	11usec	5usec	>5usec				
Vgs	-6 to 22V (surge -10V to 26V)	-4 to 22V	-6 to 20V				
Vgs op	18V	18V	15V				
Internal Rg (same size)	6.3Ω	7Ω	<3Ω				
Cgd (same size)	16nF	27nF	<<16nF				



Consider the typical half-bridge topology:





- Isolation Voltage Requirements (V_{IORM} and V_{IOWM} voltages)?
- Required Regulatory agency approvals in place?
- Automotive (AECQ) requirements?
- Creepage and clearance adequate?
- Appropriate temperature range?
- Input side supply current?
- Output drive current?
- Suitable CMR rating?
- Appropriate safety features?
- Cost and availability?

Propagation Delay Comparison example



Conditions: BM6105FW, ROHM Eval Board, VCC1=5.0V, VCC2=15V, VEE2=0V, INA=10kHz, OUT1_H/L=No Load







- Use care when selecting your Isolated DC/DC Converter. Consider the following points:
 - Breakdown Voltage Rating
 - Capacitance from Primary to Secondary (<20pF)
 - Common-Mode Rejection. Is it specified?

Suppliers of Converters include MuRata, Recom, CUI, and Mornsun

Estimated Power can be calculated from:

Pgate=Pdriver+(*Qgatefsw*∆*Vgate*)+(*C*gs*fsw*∆*Vgate*²) or approximated by $P_{DISS} \approx (C_{ISS} * 5) * (V_{CC2})^2 * fs$



Check the Gate Drive signal:

BSM180D12P2E002







(a) Measurement with standard setup (b) measurement with probe tip and ground lead removed.





Fig. 27. Comparison measured oscillation according to probing methods.



Tektronix IsoVu Probe is the best (\$ 15k - \$20k)



SiC: A Brief Overview (Tips for Successful Use) Vgs comparison with optically isolated probe Tek PreVu M 40.0µs ガ待ち ム位置: 315µs ム倍率: 10 X Differential Probe Optically-isolated Probe 5.00 ¥ Z 4.00 µs 2.50GS/s 201月 Ω 2017 6.505 % 1M points 9.60 V 14: 32: 41 (R1) 5.00 V Z 4.00µs



Check to see that $V_{(BR)DSS}$ is not exceeded:

• What is the peak voltage from Source to Drain? Remember the *allowable voltage goes* DOWN as the *temperature goes* DOWN:



Fig. 5. Measured breakdown voltage VBR(DSS) versus junction temperature Tj (°C) for a 1200 V/50-A commercial SiC power MOSFET. For comparison, data sheet values are also shown along with measurement conditions.



Measurement Circuit	Inductive Load Chopper
Current	600A
Drain Voltage	800V
Gate Voltage	On 18V / Off 0V
Gate Resistance	0.2ohm
Inductive Load	250uH
Junction Temperature	25°, 125°
Snubber Circuit	C-Snubber (1.2uF) Nippon Chemi-con HACD1C2V125JTLJ Z0
Gate Drive IC	ROHM BM6103
Oscilloscope	YOKOGAWA DL7480
Differential Voltage Prove	YOKOGAWA 700924, 701921



 V_{DC} + Voltage surge is under 1150V in this condition.

* These data are provided to show a result of evaluation done by ROHM for your reference. ROHM does not guarantee any of the characteristics shown here.





Remember to use enough dead-time! We recommend starting with 200 nanoseconds.

If you are using an optically isolated driver, check the datasheet for propagation delay vs. temperature.

Remember, MOSFETs take longer to turn-off at **minimum** load current, *not maximum load*!

Use a Rogowski Current Probe to check for shoot-through.

SiC MOSFETS tolerate only about 5 – 10 usec of overcurrent before shorting.

Use a snubber if needed







Confidential



Capacitor (Murata) KR355WD72J564MH01 (630V_{DC})



(2 parallel)

Note:

The capacitor has been mass produced. The snubber module is only for evaluation use.



Figure 1: D. Gautam, F. Musavi, M. Edington, W. Eberle "An Automotive On-Board 3.3 kW Battery Charger for PHEV Application", Delta-Q Technologies Corp.

Figure 5: "Future Prospects of Widebandgap (WBG) Semiconductor Power Switching Devices" Krishna Shenai, 2015 IEEE Transactions on Electron Devices

Figure 7: IXYS SiC Power MOSFET Data Sheet IXFN50N120SiC 2018 P.6

Page 22 Pictures: "Driving and Layout Requirements for Fast Switching MOSFETs" Won-suk Choi, Dong-kook Son, Markus Hallenberger and Sungmo Young, Fairchild Semiconductor Power Seminar 2010-2011



https://www.mouser.com/new/rohmsemiconductor/rohm-sic-power-devices/

https://www.mouser.com/new/rohmsemiconductor/rohm-sic-power-modules/

https://www.mouser.com/new/rohmsemiconductor/rohm-sic-power-mosfet/

https://www.mouser.com/new/rohmsemiconductor/rohm-sic-schottky-barrier-diodes/

https://www.mouser.com/new/rohmsemiconductor/rohm-aec-q101-sic-power-mosfets/

ROHM

ROHM Co., Ltd. © 2019 ROHM Co., Ltd.